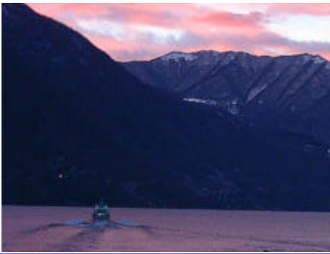

12th IEEE International On-Line Testing Symposium
Lake of Como, Italy
July 10-12, 2006

Call for Papers

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Issues related to on-line testing are increasingly important in modern electronics systems. In particular, the huge complexity of electronic systems has led to growth in reliability needs in several application domains as well as pressure for low cost products. There is a corresponding increasing demand for cost-effective on-line testing techniques. These needs have increased dramatically with the introduction of very deep submicron and nanometer technologies. Nanometer technologies adversely impact noise margins and make integrating on-line test mandatory in many modern ICs. The Symposium is also emphasizing on-line testing in the continuous operation of large applications such as wired, cellular and satellite telecommunication, as well as in secure chips. The Symposium is sponsored by the IEEE Computer Society Test Technology Technical Council (TTTC), co-organized by the TTTC On-line Testing TAC and the European Group of TTTC, in collaboration with TIMA Laboratory and University of Bologna.

The topics include (but are not limited to) the following ones:

- Reliability issues in nanometer technologies
- Field diagnosis, maintainability and reconfiguration
- On-line testing of analog and mixed signal circuits
- On-line test in the continuous operation of large systems
- On-line testing in automotive, railway and avionics
- On-line testing in industrial control
- On-line monitoring of current, temperature and other reliability indicators
- Self-checking circuits and coding theory
- On-line and off-line BIST
- Synthesis of on-line testable circuits
- Fault-tolerant and fail-safe systems
- Dependability evaluation
- On-line power monitoring and control
- Radiation effects
- Secure circuit design
- Fault-based attacks and counter measures

Submissions:

The IOLTS Program Committee invites authors to submit papers in the above areas. All submissions should have a title page with the name, address, phone number, fax number, and e-mail address of the contact author. Accepted papers will be included in formal Proceedings **to be published by the IEEE.** Papers must be submitted electronically in PDF via the Symposium Web site.

Please observe the following key dates:

Submission deadline: **February 3rd, 2006**
Notification of acceptance: **March 25th, 2006**

Submission Information

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About the location: Como Lake is the third biggest Italian lake. A few kilometers from the Switzerland border, from the Milan Malpensa airport and from Milan, it is easily reachable by air (with direct flights to Malpensa from all major international airports), by car, as well as by train. It is situated in a unique and rich environment, where within a few miles of industrial areas you can find the mountains, the lake, and the beautiful valleys of the Alps.

For all updated information concerning IOLTS 2006, please visit the Web site.

Web Site: tima.imag.fr/conferences/iolts